Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/601,899	WAN ET AL.	
Examiner	Art Unit	
Nicholas T. La	2617	

	SEARCHED		
Class	Subclass	Date	Examiner
Updated	from previous search	7/17/2006	NL

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u>.</u>		

SEARCH (INCLUDING SEA		iY)
	DATE	EXMR
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